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January 2013

FDT86106LZ

N-Channel PowerTrench[®] MOSFET 100 V, 3.2 A, 108 m Ω

Features

- Max $r_{DS(on)}$ = 108 m Ω at V_{GS} = 10 V, I_D = 3.2 A
- Max $r_{DS(on)}$ = 153 m Ω at V_{GS} = 4.5 V, I_D = 2.7 A
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability in a widely used surface mount package
- HBM ESD protection level > 3 KV typical (Note 4)
- 100% UIL tested
- RoHS Compliant

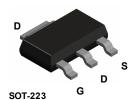


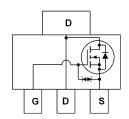
General Description

This N-Channel logic Level MOSFETs are produced using Fairchild Semiconductor's advanced Power Trench[®] process that has been special tailored to minimize the on-state resistance and yet maintain superior switching performance. G-S zener has been added to enhance ESD voltage level.

Application

■ DC - DC Conversion





MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Param	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		100	V	
V _{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current -Continuous	T _A = 25 °C	(Note 1a)	3.2	
	-Pulsed			12	A
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	12	mJ
D	Power Dissipation	T _A = 25 °C	(Note 1a)	2.2	W
P_{D}	Power Dissipation $T_A = 25 ^{\circ}\text{C}$ (Note 1b)			1.0	VV
T _J , T _{STG}	Operating and Storage Junction Temper	Operating and Storage Junction Temperature Range			°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	12	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	55	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
86106LZ	FDT86106LZ	SOT-223	13 "	12 mm	2500 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	ncteristics					
BV_DSS	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25 °C		71		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μА
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ

On Characteristics (Note 2)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.5	2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-5		mV/°C
	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 3.2 A		80	108	mΩ
r		$V_{GS} = 4.5 \text{ V}, I_D = 2.7 \text{ A}$		100	153	
r _{DS(on)}		$V_{GS} = 10 \text{ V}, I_D = 3.2 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		140	189	
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 3.2 A		8		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 50 V V - 0 V	234	315	pF
Coss	Output Capacitance	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz	46	65	pF
C _{rss}	Reverse Transfer Capacitance	1 141112	3.1	5	pF

Switching Characteristics

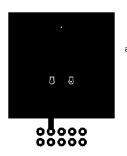
t _{d(on)}	Turn-On Delay Time		3.8	10	ns
t _r	Rise Time	V _{DD} = 50 V, I _D = 3.2 A,	1.3	10	ns
t _{d(off)}	Turn-Off Delay Time	V_{DD} = 50 V, I_{D} = 3.2 A, V_{GS} = 10 V, R_{GEN} = 6 Ω	10	20	ns
t _f	Fall Time		1.5	10	ns
Q_q	Total Gate Charge	V _{GS} = 0 V to 10 V	4.3	7	nC
Q_q	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$ $V_{DD} = 50 \text{ V},$	2.4	4	nC
Q_{gs}	Gate to Source Gate Charge	I _D = 3.2 A	0.7		nC
Q_{qd}	Gate to Drain "Miller" Charge		0.9		nC

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 3.2 \text{ A}$ (Note 2)	0.86	1.3	V
		$V_{GS} = 0 V, I_S = 1 A$ (Note 2)	0.77	1.2	v
t _{rr}	Reverse Recovery Time	I _E = 3.2 A, di/dt = 100 A/μs	31	49	ns
Q _{rr}	Reverse Recovery Charge	T _F = 3.2 A, αι/αι = 100 A/μs	21	34	nC

Notes:

 R_{0JC} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



a) 55 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 118 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. Starting $\rm T_J$ = 25 $^{\circ}\rm C$, L = 1 mH, $\rm I_{AS}$ = 5 A, $\rm V_{DD}$ = 90 V, $\rm V_{GS}$ = 10 V.
- 4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

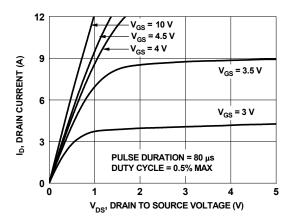


Figure 1. On-Region Characteristics

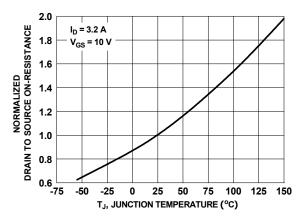


Figure 3. Normalized On-Resistance vs Junction Temperature

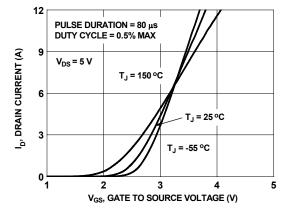


Figure 5. Transfer Characteristics

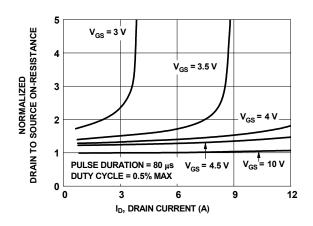


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

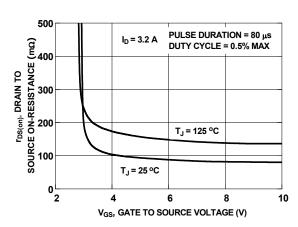


Figure 4. On-Resistance vs Gate to Source Voltage

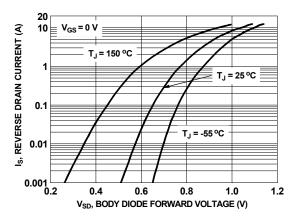


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 $^{\circ}$ C unless otherwise noted

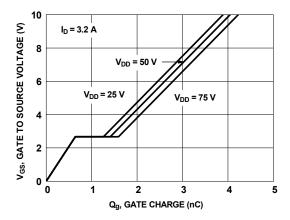


Figure 7. Gate Charge Characteristics

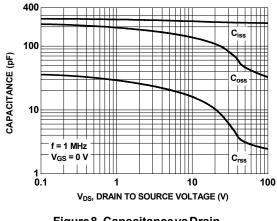


Figure 8. Capacitance vs Drain to Source Voltage

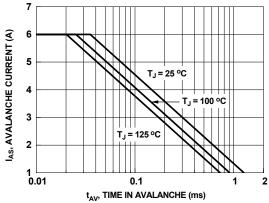


Figure 9. Unclamped Inductive Switching Capability

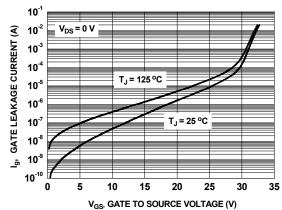


Figure 10. Gate Leakage Current vs Gate to Source Voltage

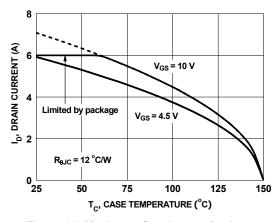


Figure 11. Maximum Continuous Drain Current vs Case Temperature

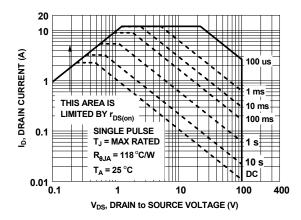


Figure 12. Forward Bias Safe Operating Area



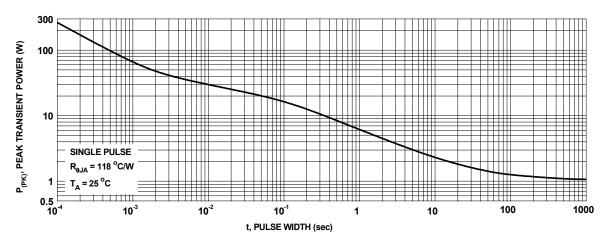


Figure 13. Single Pulse Maximum Power Dissipation

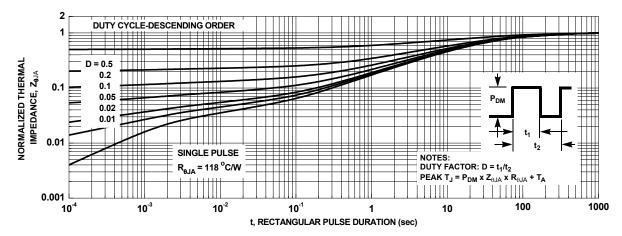
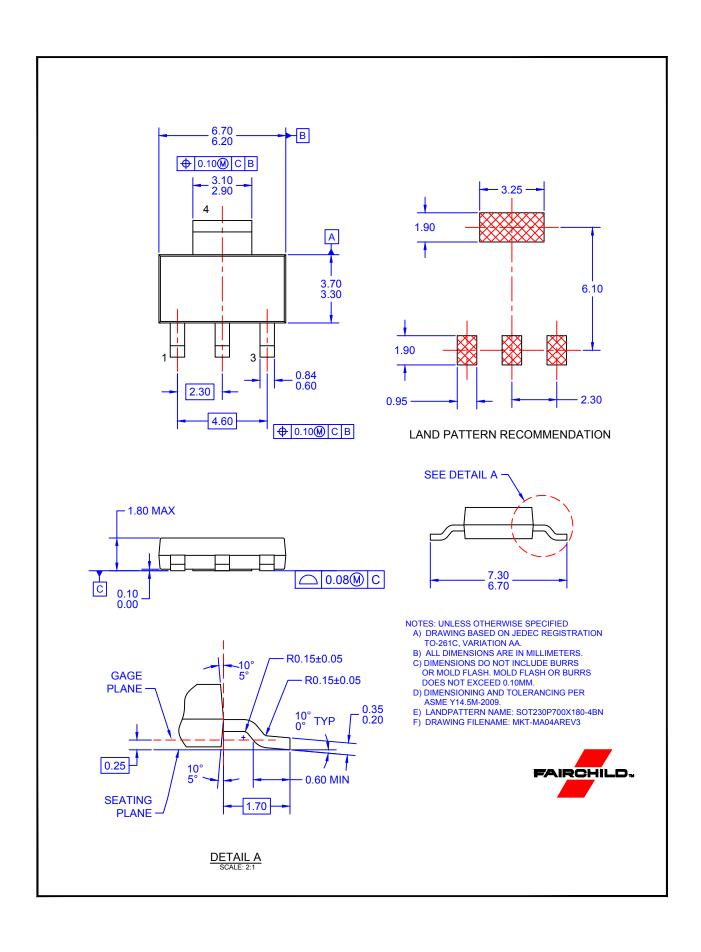


Figure 14. Junction-to-Ambient Transient Thermal Response Curve



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